

Chapter 6. *pn*-junction diode: I-V characteristics

- **Topics:** steady state response of the *pn* junction diode under applied d.c. voltage.

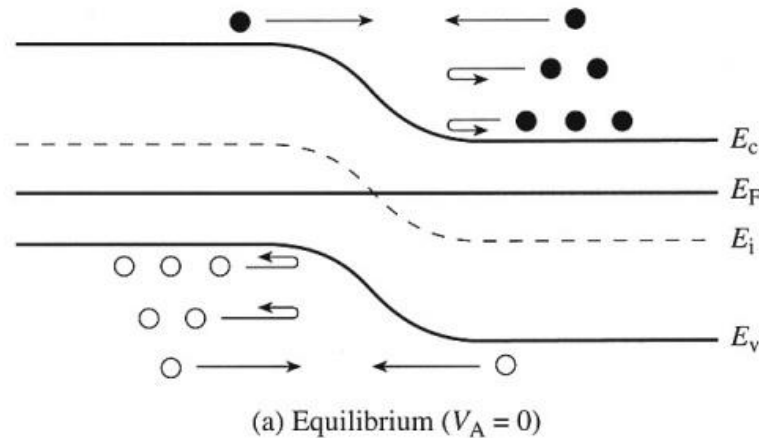
pn Junction under bias (qualitative discussion)

Ideal diode equation

Deviations from the ideal diode

Charge-control approach

Carrier flow in equilibrium



Electron diffusion current is precisely balanced by electron drift current.

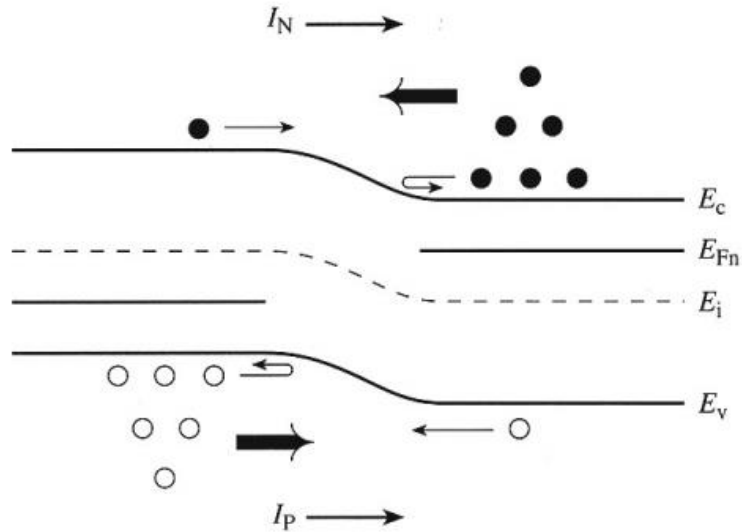
$$I_{n|drift} = I_{n|diffusion}$$

hole diffusion current is also balanced by hole drift current.

$$I_{p|drift} = I_{p|diffusion}$$

Thus, no net current across the junction.

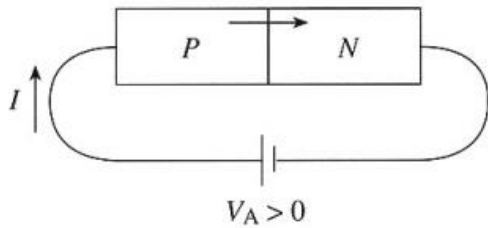
Carrier flow under forward bias



$$I_{n|drift} < I_{n|diffusion}$$

$$I_{p|drift} < I_{p|diffusion}$$

} from p - to n - side

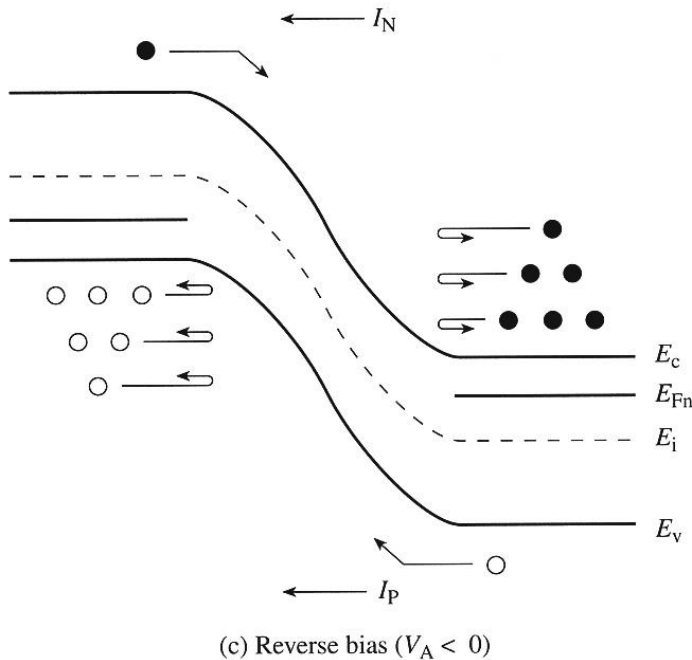


(b) Forward bias ($V_A > 0$)

As the potential hill **linearly** decreases with the **forward bias**, the **number of majority carriers** which have sufficient energy to **surmount** the potential barrier **exponentially** goes up with V_A .

It is expected that **forward current** (i.e., **majority carrier diffusion current**) **exponentially** increases with V_A .

Carrier flow under reverse bias



The majority carrier diffusion across the junction is negligible.

The minority carrier drift is still allowed to flow the reverse current (i.e., minority carrier drift current) across the junction (from n- to p-side).

The reverse current is expected to be extremely small in magnitude, due to the low concentration of the minority carriers.

As V_A negatively increases, the reverse current is also expected to saturate, once the majority carrier diffusion currents are reduce to a negligible level at a small bias.

Ch 6-1 The ideal diode equation

$$\text{Net current} = I_{\text{diff}} - I_{\text{drift}}$$

At equilibrium ($V_A = 0$), net current = 0

$$\text{set } |I_{\text{diff}}|_{V_A=0} = |I_{\text{drift}}|_{V_A=0} = I_0$$

$|I_{\text{drift}}|$ saturates and does not change with V_A (Why?)

Because the drift current is limited **NOT** by **HOW FAST** carriers are swept across the depletion layer, but rather **HOW OFTEN**. → think a waterfall !

$|I_{\text{diff}}|$ varies exponentially with V_A (Why?)

Because the **number of carriers** which have sufficient energy **to surmount** the potential barrier **exponentially goes up** with V_A .

Ch 6-1 The ideal diode equation

$|I_{diff}| = I_0 \exp(V_A/V_{ref})$ where I_0 and V_{ref} are constants.

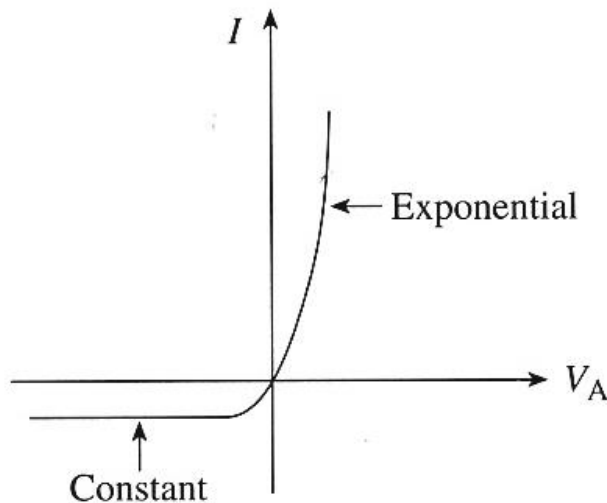
At any applied voltage, V_A ,

$$I = I_0 e^{V_A/V_{ref}} - I_{drift}$$

since $I_{drift} = I_0$ at any voltage.

$$= I_0 e^{V_A/V_{ref}} - I_0$$

$$= I_0 (e^{V_A/V_{ref}} - 1)$$

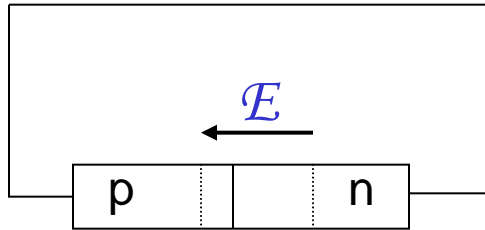


$$I = I_0 (e^{V_A/V_{ref}} - 1)$$

Predicted equation for
ideal diodes

pn junction under various bias conditions

$$V_A = 0$$



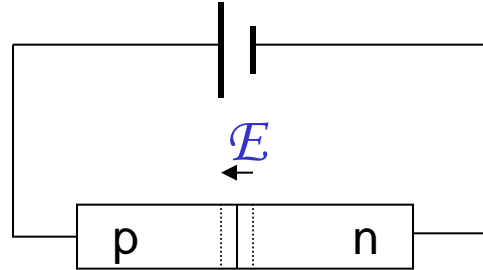
Majority hole diffusion current

Minority hole drift current

Majority electron diffusion current

Minority electron drift current

$$V_A > 0$$



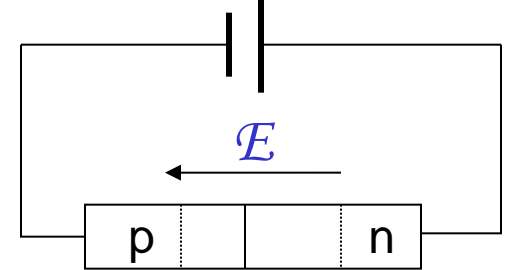
Majority hole diffusion current

Minority hole drift current

Majority electron diffusion current

Minority electron drift current

$$V_A < 0$$



Majority hole diffusion current

Minority hole drift current

Majority electron diffusion current

Minority electron drift current

Ideal diode equation: quantitative solution

- Assumptions which must hold
 - The diode is being operated under **steady state** conditions
 - A **non-degenerately doped step junction** models the doping profile
 - The diode is **one-dimensional**
 - **Low-level injection** prevails in the **quasi-neutral regions**
 - There are no processes other than drift, diffusion, and thermal recombination-generation taking place inside the diode, specifically, $G_L=0$

Ideal diode equation: quantitative solution

We want to obtain a **current equation** of diode against V_A .

Therefore the **total current** can be obtained from the **total current density** (J).

$$I = AJ$$

Note that the **total current density** (J) is **constant** throughout the diode under the steady state, but the J_n and J_p **vary with position**.

$$J = J_n(x) + J_p(x)$$

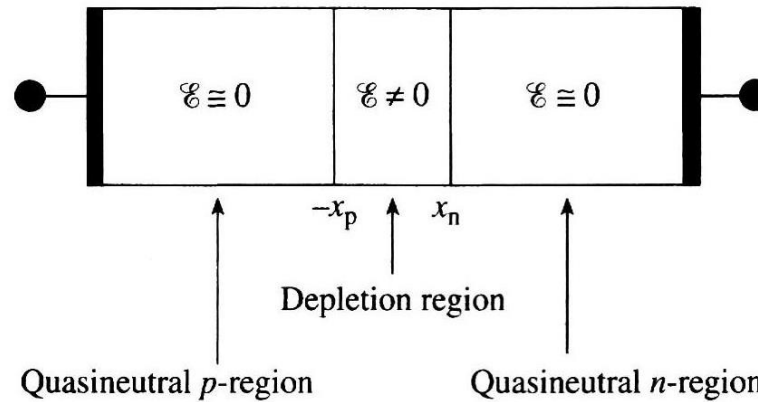
The $J_n(x)$ and $J_p(x)$ should be expressed as a function of x by using the following equations,

$$J_n = q\mu_n nE + qD_n \frac{dn}{dx} \qquad J_p = q\mu_p pE + qD_p \frac{dp}{dx}$$

The n and p can be evaluated by using the **continuity equation**.

Ideal diode equation: quantitative solution

Quasi-neutral region consideration



Let's consider the $J_n(x)$ and $J_p(x)$ in the **quasi-neutral regions**, because the **continuity equation** can be simplified to the **minority carrier diffusion equation** in this region (note that $\mathcal{E} \approx 0$ and the **low level injection** assumption).

Minority carrier
diffusion equation

$$\frac{\partial \Delta n_p}{\partial t} = D_n \frac{\partial^2 \Delta n_p}{\partial x^2} - \frac{\Delta n_p}{\tau_n} + G_L$$

for **electrons** in **p-type**

$$\frac{\partial \Delta p_n}{\partial t} = D_p \frac{\partial^2 \Delta p_n}{\partial x^2} - \frac{\Delta p_n}{\tau_p} + G_L$$

for **holes** in **n-type**

Ideal diode equation: quantitative solution

Quasi-neutral region consideration

Under the assumption of the **steady state** with $G_L = 0$,

Already we know the general solution

$$\left\{ \begin{array}{l} 0 = D_n \frac{\partial^2 \Delta n_p}{\partial x^2} - \frac{\Delta n_p}{\tau_n} \quad x \leq -x_p \\ 0 = D_p \frac{\partial^2 \Delta p_n}{\partial x^2} - \frac{\Delta p_n}{\tau_p} \quad x \geq x_n \end{array} \right.$$

$$\Delta n_p(x) = Ae^{-x/L_n} + Be^{x/L_n} \quad \Delta p_n(x) = Ae^{-x/L_p} + Be^{x/L_p}$$

Since $\mathcal{E} \approx 0$ and $dn_0/dx = dp_0/dx = 0$ in the quasi-neutral region, (note that $n = n_0 + \Delta n$ and $p = p_0 + \Delta p$)

$$J_n = q\mu_n n \mathcal{E} + qD_n \frac{dn}{dx} \longrightarrow J_n = qD_n \frac{d\Delta n_p}{dx} \quad x \leq -x_p$$

$$J_p = q\mu_p p \mathcal{E} + qD_p \frac{dp}{dx} \longrightarrow J_p = qD_p \frac{d\Delta p_n}{dx} \quad x \geq x_n$$

Ideal diode equation: quantitative solution

Depletion region consideration

In the depletion region, $E \neq 0$ so, the continuity equation must be used under our assumptions (steady state and only thermal R-G process).

$$\frac{\partial n}{\partial t} = \frac{1}{q} \frac{\partial J_n}{\partial x} + \frac{\partial n}{\partial t} \Big|_{\text{thermal R-G}} + \frac{\partial n}{\partial t} \Big|_{\text{others (light etc.)}} \longrightarrow 0 = \frac{1}{q} \frac{\partial J_n}{\partial x} + \frac{\partial n}{\partial t} \Big|_{\text{thermal R-G}}$$

$$\frac{\partial p}{\partial t} = -\frac{1}{q} \frac{\partial J_p}{\partial x} + \frac{\partial p}{\partial t} \Big|_{\text{thermal R-G}} + \frac{\partial p}{\partial t} \Big|_{\text{others (light etc.)}} \longrightarrow 0 = -\frac{1}{q} \frac{\partial J_p}{\partial x} + \frac{\partial p}{\partial t} \Big|_{\text{thermal R-G}}$$

Additionally, we can assume that thermal R-G process is negligible throughout the depletion region.

$$\text{Thus, } 0 = \frac{\partial J_n}{\partial x} \quad \text{and} \quad 0 = \frac{\partial J_p}{\partial x} \quad \text{at } -x_p \leq x \leq x_n$$

Ideal diode equation: quantitative solution

Depletion region consideration

$$0 = \frac{\partial J_n}{\partial x} \quad \text{and} \quad 0 = \frac{\partial J_p}{\partial x} \quad \text{at} \quad -x_p \leq x \leq x_n$$

This reveals the constancy of the carrier currents throughout the depletion region (including the edges).

$$J_n(-x_p \leq x \leq x_n) = J_n(-x_p) = J_n(x_n)$$

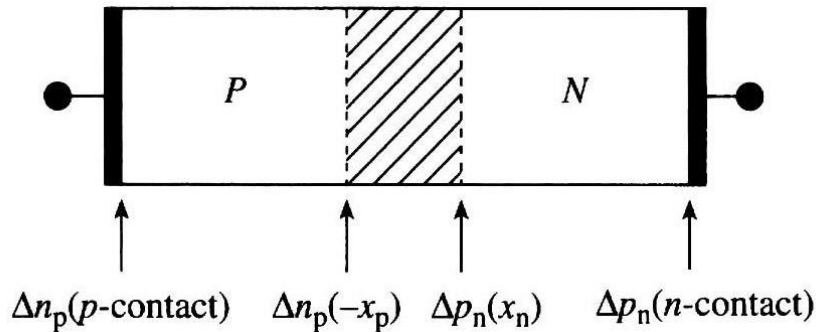
$$J_p(-x_p \leq x \leq x_n) = J_p(-x_p) = J_p(x_n)$$

Summing two equations,

$$J = J_n(-x_p) + J_p(x_n)$$

Ideal diode equation: quantitative solution

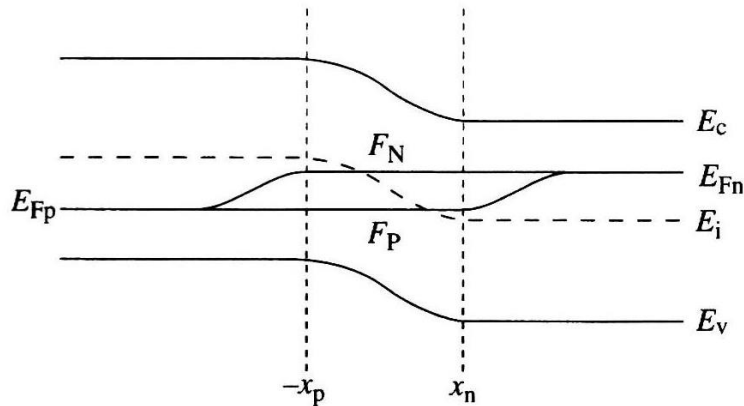
Boundary conditions



If the ohmic contacts are far enough from the edges of the depletion region, the boundary conditions at the ohmic contacts will be

$$\Delta n_p(x \rightarrow -\infty) = 0$$

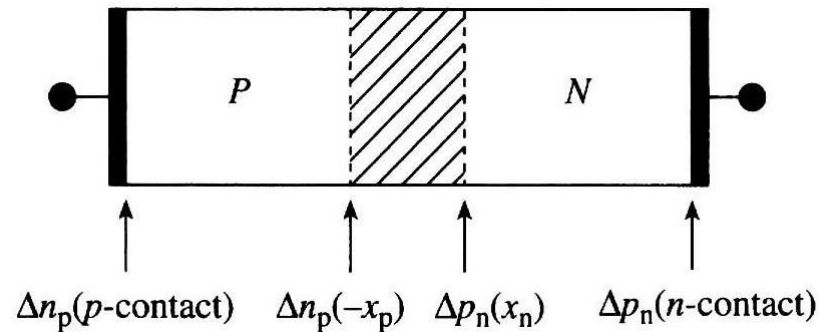
$$\Delta p_n(x \rightarrow +\infty) = 0$$



[Band diagram inside a forward-biased diode]

Ideal diode equation: quantitative solution

Boundary conditions



To establish the **boundary conditions** at the **edges of the depletion region**, consider the definition of the **quasi-Fermi levels**.

$$F_p \equiv E_i - kT \ln\left(\frac{p}{n_i}\right)$$

$$F_n \equiv E_i + kT \ln\left(\frac{n}{n_i}\right)$$

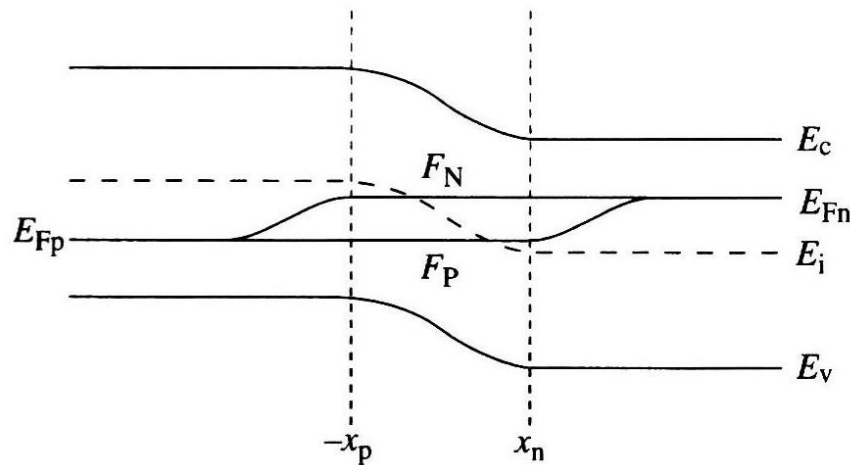
$$n = n_i e^{\left(\frac{F_n - E_i}{kT}\right)}$$

$$p = n_i e^{\left(\frac{E_i - F_p}{kT}\right)}$$

Thus, $np = n_i^2 e^{\left(\frac{F_n - F_p}{kT}\right)}$

Ideal diode equation: quantitative solution

Boundary conditions



$$np = n_i^2 e^{\left(\frac{F_n - F_p}{kT}\right)}$$

$$E_{Fn} - E_{Fp} = qV_A$$

[F_p and F_n variation inside a forward-biased diode]

Assuming $F_n - F_p = qV_A$, $F_n = E_{Fn}$ and $F_p = E_{Fp}$ throughout the depletion region,

$$F_n - F_p \leq E_{Fn} - E_{Fp} = qV_A$$

Therefore,
$$np = n_i^2 e^{qV_A/kT} \quad -x_p \leq x \leq x_n$$

This equation is referred to as the “**law of the junction**”.

Ideal diode equation: quantitative solution

Boundary conditions

$$np = n_i^2 e^{qV_A/kT} \quad -x_p \leq x \leq x_n$$

At the **p-edge** of the depletion region,

$$n(-x_p)p(-x_p) = n(-x_p)N_A = n_i^2 e^{qV_A/kT} \quad \text{or} \quad n(-x_p) = \frac{n_i^2}{N_A} e^{qV_A/kT}$$

$$\text{Then, } \Delta n_p(-x_p) = n_p(-x_p) - n_{p0}(-x_p) = \frac{n_i^2}{N_A} e^{qV_A/kT} - \frac{n_i^2}{N_A}$$

$$\Delta n_p(-x_p) = \frac{n_i^2}{N_A} (e^{qV_A/kT} - 1)$$

Similarly at the **n-edge**,

$$\Delta p_n(x_n) = \frac{n_i^2}{N_D} (e^{qV_A/kT} - 1)$$

Plan for the quantitative solution

1) Solve the minority carrier diffusion equations employing boundary conditions

$$0 = D_n \frac{\partial^2 \Delta n_p}{\partial x^2} - \frac{\Delta n_p}{\tau_n} \quad x \leq -x_p$$

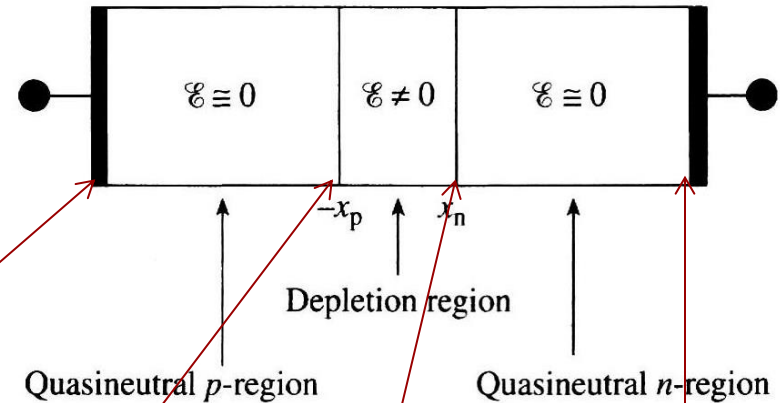
$$0 = D_p \frac{\partial^2 \Delta p_n}{\partial x^2} - \frac{\Delta p_n}{\tau_p} \quad x \geq x_n$$

$$\Delta n_p(x) = Ae^{-x/L_n} + Be^{x/L_n}$$

$$\Delta p_n(x) = Ae^{-x/L_p} + Be^{x/L_p}$$

$$\Delta n_p(x \rightarrow -\infty) = 0$$

$$\Delta n_p(-x_p) = \frac{n_i^2}{N_A} (e^{qV_A/kT} - 1)$$



$$\Delta p_n(x \rightarrow +\infty) = 0$$

$$\Delta p_n(x_n) = \frac{n_i^2}{N_D} (e^{qV_A/kT} - 1)$$

Plan for the quantitative solution

2) Compute the minority carrier current densities in the quasi-neutral regions using

$$\left\{ \begin{array}{ll} J_n = qD_n \frac{d\Delta n_p}{dx} & x \leq -x_p \\ J_p = qD_p \frac{d\Delta p_n}{dx} & x \geq x_n \end{array} \right.$$

3) Evaluate the quasi-neutral region solutions for $J_n(x)$ and $J_p(x)$ at the edges of the depletion region and then sum the two edge current densities.

$$J = J_n(-x_p) + J_p(x_n)$$

4) Finally, multiply the result by the cross-sectional area of the diode.

$$I = AJ$$

Announcements

- Next lecture: p. 247 ~ 259